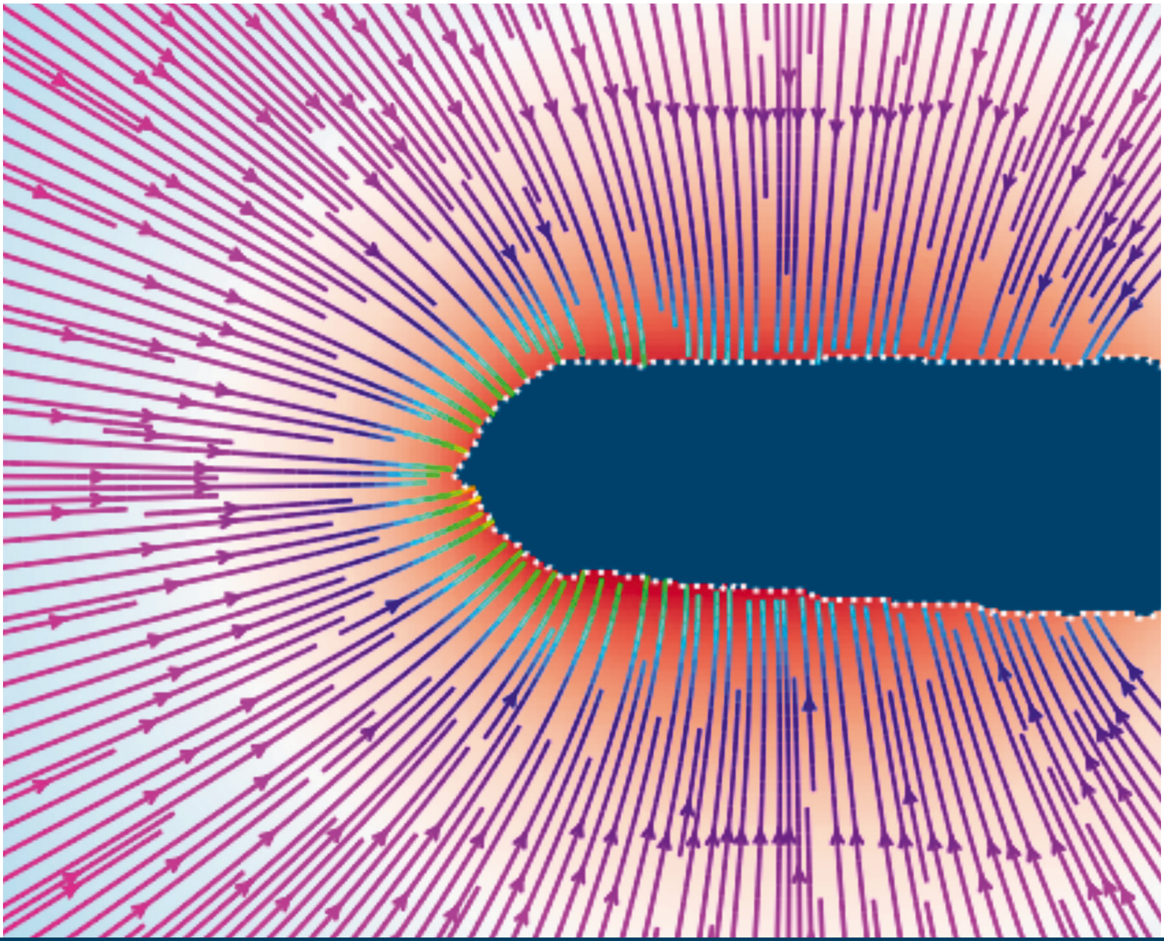

High spatial resolution and three-dimensional measurement of charge density and electric field in nanoscale materials using off-axis electron holography

Fengshan Zheng

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Table of contents

List of figures ix

List of tables xv

Nomenclature xvii

1 Introduction **1**

1.1 Importance of local charge density and electric field measurement 1

1.1.1 Charge accumulation at interfaces and surfaces of materials 1

1.1.2 Electron-beam-induced charging 2

1.1.3 Cold field emission 3

1.1.4 Atom probe tomography 4

1.2 Charge density and electric field measurement in the TEM 5

1.3 Relationship to SIMDALEE2 6

2 Fundamentals **9**

2.1 Off-axis electron holography 9

2.2 Charge density measurement using off-axis electron holography 12

2.2.1 Model-independent approach 12

2.2.2 Analytical model-dependent approach 13

3 Experimental setup and choice of specimens **15**

3.1 Off-axis electron holography in the TEM 15

3.2 Electrical biasing setup 16

3.3 Electron-beam-induced charging setup 17

3.4 Overview of specimens 17

3.4.1 W nanotip 17

3.4.2 LaB_6 field emitter 17

3.4.3 W_5O_{14} nanowire 18

3.4.4 CdS nanocomb 18
3.4.5 Carbon fibre needle 18
3.4.6 Cr_2AlC-Al_2O_3 atom probe needle 18

4 Applications of model-independent and analytical model-dependent approaches for charge density measurement to needle-shaped specimens 21
4.1 Model-independent approach: practical considerations 21
4.1.1 Mean inner potential 22
4.1.2 Spatial resolution 24
4.1.3 Signal-to-noise ratio 24
4.2 Application of model-independent and analytical model-dependent approaches 30
4.2.1 Model-independent charge density reconstruction 31
4.2.2 Analytical model-dependent reconstruction 31
4.3 Discussion 36
4.4 Summary and conclusions 36

5 Development of model-based iterative reconstruction approach 39
5.1 Overview 40
5.2 Forward model 42
5.3 Regularisator 43
5.4 Charge density reconstruction in projection 44
5.4.1 Mask 45
5.4.2 Gaussian noise and regularisation strength 47
5.4.3 Confidence mask 50
5.4.4 Charges outside the field of view 53
5.4.5 Perturbed reference wave 53
5.4.6 Reconstruction from an experimental phase image 55
5.5 Charge density reconstruction in three dimensions 59
5.5.1 3D mask 59
5.5.2 3D buffer pixel approach 62
5.6 Uniqueness of reconstruction 66
5.6.1 Reconstruction of projected charge density 66
5.6.2 Reconstruction of 3D charge density 68
5.7 Summary and conclusions 71

6 Charge density measurement in a W_5O_{14} field emitter 73
6.1 Geometry and experimental setup 73

6.2 Field emission 77
6.3 Model-independent reconstruction of charge density 81
6.3.1 Mean inner potential contribution to the phase 81
6.3.2 Cumulative charge profiles 82
6.4 Analytical model-dependent measurement of charge density 87
6.4.1 Nonlinear line charge density 87
6.4.2 Field enhancement factor and emission current 89
6.5 Model-based iterative reconstruction of charge density 91
6.6 Discussion 96
6.6.1 Model-independent, model-dependent and model-based iterative reconstruction 96
6.6.2 Comparison with results from a CdS nanocomb 98
6.7 Summary and conclusions 100

7 Charge density measurement in a carbon fibre needle **101**
7.1 Electrical biasing setup 101
7.2 3D reconstruction of charge, electric field and electrostatic potential 103
7.2.1 3D data acquisition 103
7.2.2 3D mask 103
7.2.3 3D charge, electric field and electrostatic potential 105
7.3 Summary and conclusions 113

8 Measurement of electron-beam-induced charging **115**
8.1 Specimen geometry and morphology 115
8.2 Electron-beam-induced charging 117
8.3 Dose rate dependence 119
8.4 Temperature dependence 121
8.5 Bias voltage dependence 123
8.6 Examination of an additional needle 126
8.6.1 Temperature dependence 128
8.6.2 Influence of plasma cleaning 132
8.6.3 Accelerating voltage dependence 134
8.7 Summary and conclusions 138

9 Discussion **139**
9.1 Applicability of approaches 139
9.2 Significance of experimental measurements 141

9.3 Potential for use in a combined APT-TEM instrument 142
9.4 Conclusions in the context of the SIMDALEE2 project 143

10 Conclusions and outlook **145**

Bibliography **149**

Appendix A Elementary expressions for phase and electric field **161**
A.1 Preliminary knowledge 161
A.2 Phase of a point charge 162
A.3 Uniformly-charged sphere 162

Appendix B Analytical line charge models for a needle-shaped geometry **167**
B.1 Constant line charge model 167
B.2 Linear line charge model 168

Appendix C Analytical model-dependent approach for the W_5O_{14} nanowire **171**
C.1 Analytical and numerical modelling 171
C.2 Fitting of charge density and cumulative charge 176
C.3 Rounded cylindrical needle on a conducting plane 179

Acknowledgements **182**

List of publications **185**

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